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|-----------------------------------|--|-------------------------|--|---|
| Notice of References Cited | | Application/Control No. | Applicant(s)/Patent Under Reexamination 10/613,634 CHEN ET AL. | |
| | | Examiner | Art Unit | Page 1 of 1 Michael P. Stafira 2877 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-------------------|----------------|
| | A | US-5,808,735 | 09-1998 | Lee et al. | 356/237.2 |
| | B | US-5,301,129 | 04-1994 | McKaughan et al. | 382/149 |
| | C | US-6,195,444 | 02-2001 | Simanovsky et al. | 382/100 |
| | D | US-6,266,437 | 07-2001 | Eichel et al. | 382/149 |
| | E | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| | | |
|---|---|---|
| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
| | U | |
| | V | |
| | W | |
| | X | |

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